

SEMICONDUCTOR

74F253 Dual 4-Input Multiplexer with 3-STATE Outputs

General Description

The 74F253 is a dual 4-input multiplexer with 3-STATE outputs. It can select two bits of data from four sources using common select inputs. The output may be individually switched to a high impedance state with a HIGH on the respective Output Enable (\overline{OE}) inputs, allowing the outputs to interface directly with bus oriented systems.

Features

- Multifunction capability
- Non-inverting 3-STATE outputs

April 1988

Revised August 1999

Ordering Code:

Ordening C	ode:	2
Order Number	Package Number	Package Description
74F253SC	M16A	16-Lead Small Outline Integrated Circuit (SOIC), JEDEC MS-012, 0.150 Narrow
74F253SJ	M16D	16-Lead Small Outline Package (SOP), EIAJ TYPE II, 5.3mm Wide
74F253PC	N16E	16-Lead Plastic Dual-In-Line Package (PDIP), JEDEC MS-001, 0.300 Wide



© 1999 Fairchild Semiconductor Corporation DS009505

74F253

Unit Loading/Fan Out

Pin Names	Description	U.L.	Input I _{IH} /I _{IL}		
	Description	HIGH/LOW	Output I _{OH} /I _{OL}		
I _{0a} –I _{3a}	Side A Data Inputs	1.0/1.0	20 µA/–0.6 mA		
I _{0b} –I _{3b}	Side B Data Inputs	1.0/1.0	20 µA/–0.6 mA		
S ₀ –S ₁	Common Select Inputs	1.0/1.0	20 µA/–0.6 mA		
OE _a	Side A Output Enable Input (Active LOW)	1.0/1.0	20 µA/–0.6 mA		
OEb	Side B Output Enable Input (Active LOW)	1.0/1.0	20 µA/–0.6 mA		
Z _a , Z _b	3-STATE Outputs	150/40(33.3)	–3 mA/24 mA (20 mA)		

Functional Description

This device contains two identical 4-input multiplexers with 3-STATE outputs. They select two bits from four sources selected by common Select inputs (S₀, S₁). The 4-input multiplexers have individual Output Enable (\overline{OE}_a , \overline{OE}_b) inputs which, when HIGH, force the outputs to a high impedance (High Z) state. This device is the logic implementation of a 2-pole, 4-position switch, where the position of the switch is determined by the logic levels supplied to the two select inputs. The logic equations for the outputs are shown below:

$$\begin{split} Z_a &= \overline{OE}_a \bullet (I_{0a} \bullet \overline{S}_1 \bullet \overline{S}_0 + I_{1a} \bullet \overline{S}_1 \bullet S_0 + \\ I_{2a} \bullet S_1 \bullet \overline{S}_0 + I_{3a} \bullet S_1 \bullet S_0) \\ Z_b &= \overline{OE}_b \bullet (I_{0b} \bullet \overline{S}_1 \bullet \overline{S}_0 + I_{1b} \bullet \overline{S}_1 \bullet S_0 + \\ I_{2b} \bullet S_1 \bullet S_0 + I_{3b} \bullet S_1 \bullet S_0) \end{split}$$

designed so that there is no overlap.

If the outputs of 3-STATE devices are tied together, all but one device must be in the high impedance state to avoid high currents that would exceed the maximum ratings. Designers should ensure that Output Enable signals to 3-STATE devices whose outputs are tied together are

Truth Table

Sel	ect		Data I	nnute		Output	Output	
Inp	uts	Data inputs				Enable	Output	
S ₀	S ₁	I ₀	I ₁	I_2	I ₃	OE	z	
Х	Х	Х	X	X	Х	Н	Z	
L	L	L,	Х	X	Х	L	L	
L	L ₂₆	H-	Х	Х	Х	L	н	
н	L	Х	L	X	X	L	L	
8.1) (
н	L	Х	н	Х	Х	L	н	
L	н	X	Х	L	Х	L	L	
L	Н	Х	Х	н	Х	L	Н	
Н	н	Х	Х	Х	L	L	L	
н	н	Х	Х	Х	н	L	н	

Address inputs S_0 and S_1 are common to both sections. H = HIGH Voltage Level

L = LOW Voltage Level

X = Immaterial





Absolute Maximum Ratings(Note 1)

Storage Temperature	$-65^{\circ}C$ to $+150^{\circ}C$
Ambient Temperature under Bias	$-55^{\circ}C$ to $+125^{\circ}C$
Junction Temperature under Bias	$-55^{\circ}C$ to $+150^{\circ}C$
$V_{\mbox{\scriptsize CC}}$ Pin Potential to Ground Pin	-0.5V to +7.0V
Input Voltage (Note 2)	-0.5V to +7.0V
Input Current (Note 2)	-30 mA to +5.0 mA
Voltage Applied to Output	
in HIGH State (with $V_{CC} = 0V$)	
Standard Output	–0.5V to V _{CC}
3-STATE Output	-0.5V to +5.5V
Current Applied to Output	
in LOW State (Max)	twice the rated I_{OL} (mA)
ESD Last Passing Voltage (Min)	4000V

Recommended Operating Conditions

Free Air Ambient Temperature	
Supply Voltage	

74F253

0°C to +70°C +4.5V to +5.5V

Abasluta manimum rations are values beyond which the day

Note 1: Absolute maximum ratings are values beyond which the device may be damaged or have its useful life impaired. Functional operation under these conditions is not implied.

Note 2: Either voltage limit or current limit is sufficient to protect inputs.

DC Electrical Characteristics

SymbolParameterMinTypMaxUnitsV_ccCondition V_{IL} Input HIGH Voltage2.0VRecognized as a V_{IL} Input LOW Voltage0.8VRecognized as a V_{CD} Input Camp Diode Voltage-1.2VMin V_{OH} Output HIGH10% V_{CC}2.5VMin V_{OH} Output HIGH10% V_{CC}2.4VMin V_{OH} Output LOW10% V_{CC}2.7VMin V_{OL} Output LOW10% V_{CC}2.7VMin V_{OL} Output HIGH10% V_{CC}2.7VMin V_{OL} Output HIGH10% V_{CC}2.7VMin V_{OL} Output HIGH10% V_{CC}2.7VMin V_{OL} Output HIGH10% V_{CC}2.7VMin V_{IH} Input HIGH5.0 μA Max $V_{IN} = 7.0V$ I_{IH} Input HIGH5.0 μA Max $V_{IN} = 7.0V$ I_{ID} Input HIGH Current50 μA Max $V_{OUT} = V_{CC}$ V_{ID} Input Leakage4.75V0.0 $I_{ID} = 1.9 \mu A$ I_{OD} Test3.75 μA 0.0 $V_{IO} = 150 mV$ I_{ID} Input Leakage-0.6mAMax $V_{IN} = 0.5V$	
$ \begin{array}{c c c c c c c c c c c c c c c c c c c $	ns
$ \begin{array}{c c c c c c c c c c c c c c c c c c c $	IIGH Signal
$ \begin{array}{c c c c c c c c c c c c c c c c c c c $	OW Signal
$ \begin{array}{c ccccccccccccccccccccccccccccccccccc$	
$ \begin{array}{c c c c c c c c c c c c c c c c c c c $	
5% V _{CC} 5% V _{CC} 2.7 2.7VMill II $I_{OH} = -1 \text{ mA}$ $I_{OH} = -3 \text{ mA}$ Vol.Output LOW Voltage10% V _{CC} 0.5VMin $I_{OL} = 24 \text{ mA}$ IIInput HIGH Current5.0 μA Max $V_{IN} = 2.7V$ IBVIInput HIGH Current Breakdown Test7.0 μA Max $V_{IN} = 7.0V$ ICEXOutput HIGH Leakage Current50 μA Max $V_{OUT} = V_{CC}$ VIDInput Leakage Test4.75V0.0 $I_{ID} = 1.9 \mu A$ All Other Pins GroupIopOutput Leakage Circuit Current3.75 μA 0.0 $V_{IOD} = 150 \text{ mV}$ Input Low Current-0.6mAMax $V_{IV} = 0.5V$	
$\begin{tabular}{ c c c c c c c c c c c c c c c c c c c$	
$ \begin{array}{c c c c c c c c c c c c c c c c c c c $	
Voltage 0.5 V Will $I_{OL} = 24$ MA I _H Input HIGH 5.0 μ A Max $V_{IN} = 2.7V$ I _{BVI} Input HIGH Current 5.0 μ A Max $V_{IN} = 2.7V$ I _{BVI} Input HIGH Current 7.0 μ A Max $V_{IN} = 7.0V$ I _{CEX} Output HIGH 50 μ A Max $V_{OUT} = V_{CC}$ V _{ID} Input Leakage 4.75 V 0.0 All Other Pins Growth and the Pins Gr	
$ \begin{array}{c c c c c c c c c c c c c c c c c c c $	
Current 5.0 μ A Max $V_{IN} = 2.7 V$ I _{BVI} Input HIGH Current Breakdown Test 7.0 μ A Max $V_{IN} = 7.0 V$ I _{CEX} Output HIGH Leakage Current 50 μ A Max $V_{OUT} = V_{CC}$ V _{ID} Input Leakage Test 4.75 V 0.0 $I_{ID} = 1.9 \mu A$ AII Other Pins Group AII Other Pins Group AII Other Pins Group Iop Output Leakage Circuit Current 3.75 μ A 0.0 $V_{IOD} = 150 mV$ AII Other Pins Group Input Low Current -0.6 mA Max $V_{IIIIIIIIIIIIIIIIIIIIIIIIIIIIIIIIIIII$	
Input HIGH Current Breakdown Test Input HIGH Current Breakdown Test 7.0 μA Max $V_{IN} = 7.0V$ I _{CEX} Output HIGH Leakage Current 50 μA Max $V_{OUT} = V_{CC}$ V _{ID} Input Leakage Test 4.75 V 0.0 $I_{ID} = 1.9 \ \mu A$ All Other Pins Gro All Other Pins Gro Circuit Current Input Leakage 3.75 μA 0.0 $V_{IOD} = 150 \ mV$ All Other Pins Gro All Other Pins Gro	
Breakdown Test 7.0 μ A Max $v_{IN} = 7.0^{\circ}$ I _{CEX} Output HIGH 50 μ A Max $V_{OUT} = V_{CC}$ V _{ID} Input Leakage 4.75 V 0.0 AII Other Pins Group I _{OD} Output Leakage 3.75 μ A 0.0 AII Other Pins Group I _{DD} Input Leakage 3.75 μ A 0.0 AII Other Pins Group I _{DD} Input Leakage -0.6 mA Max $V_{V_{DD}} = 150 \text{ mV}$	
I _{CEX} Output HIGH 50 μ A Max V _{OUT} = V _{CC} V _{ID} Input Leakage 4.75 V 0.0 II _D = 1.9 μ A I _{OD} Output Leakage 4.75 V 0.0 All Other Pins Group I _{OD} Output Leakage 3.75 μ A 0.0 VIOD = 150 mV I _{ID} Input Low Current -0.6 mA Max V _{IID} = 0.5V	
Leakage Current S0 μ A Max $v_{OUT} = v_{CC}$ V _{ID} Input Leakage 4.75 V 0.0 $I_{ID} = 1.9 \ \mu$ A I _{OD} Output Leakage 4.75 V 0.0 $AII \ Other \ Pins \ Growthered \ Growthered \ Circuit \ Current$ I _u Input LOW Current -0.6 mA Max $V_{uv} = 0.5 \ V_{uv}$	
V_{ID} Input Leakage Test 4.75 V 0.0 $I_{ID} = 1.9 \mu A$ All Other Pins Group All Other Pi	
Test 4.75 V 0.0 All Other Pins Group Iop Output Leakage 3.75 μA 0.0 Viote = 150 mV Iu Input LOW Current -0.6 mA Max Viote = 0.5V	
I _{OD} Output Leakage Circuit Current 3.75 μA 0.0 V _{IOD} = 150 mV All Other Pins Gro All Other Pins Gro In Input LOW Current -0.6 mA Max V _N = 0.5V	unded
Circuit Current 3.73 µA 0.0 All Other Pins Gro Ju Input LOW Current -0.6 mA Max V _m = 0.5V	
$1_{\rm H}$ Input LOW Current -0.6 mA Max $V_{\rm H} = 0.5V$	unded
I_{OZH} Output Leakage Current 50 μ A Max $V_{OUT} = 2.7V$	
I _{OZL} Output Leakage Current -50 μA Max V _{OUT} = 0.5V	
I_{OS} Output Short-Circuit Current -60 -150 mA Max $V_{OUT} = 0V$	
-100 -225 V _{OUT} = 0V	
I_{ZZ} Bus Drainage Test 500 μ A 0.0V $V_{OUT} = V_{CC}$	
I _{CCH} Power Supply Current 11.5 16 mA Max V _O = HIGH	
I _{CCL} Power Supply Current 16 23 mA Max V _O = LOW	
I_{CCZ} Power Supply Current 16 23 mA Max $V_0 = HIGH Z$	

Symbol			T _A = +25°C		$T_A = -55^{\circ}C$	to +125°C	T _A = 0°C	; to +70°C	
Symbol			V _{CC} = 5.0V		V _{cc} =	5.0V	V _{CC}	= 5.0V	
	Parameter		C ₁ = 50 pF		C ₁ =	50 pF	C, =	50 pF	Unit
		Min	Тур	Max	Min	Max	Min	Max	
PLH	Propagation Delay	4.5	8.5	11.5	3.5	15.0	4.5	13.0	
t _{PHL}	S _n to Z _n	3.0	6.5	9.0	2.5	11.0	3.0	10.0	ns
t _{PLH}	Propagation Delay	3.0	5.5	7.0	2.5	9.0	3.0	8.0	
t _{PHL}	I _n to Z _n	2.5	4.5	6.0	2.5	8.0	2.5	7.0	ns
t _{PZH}	Output Enable Time	3.0	6.0	8.0	2.5	10.0	3.0	9.0	
t _{PZL}		3.0	6.0	8.0	2.5	10.0	3.0	9.0	ns
t _{PHZ}	Output Disable Time	2.0	3.7	5.0	2.0	6.5	2.0	6.0	
t _{PLZ}		2.0	4.4	6.0	2.0	8.0	2.0	7.0	
		2		.0					



74F253

